

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination TU ET AL.	
		Examiner Christopher E. Lee	Art Unit 2112	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
A	US-6,237,058 B1	05-2001	Nakagawa, Toshikazu	710/260
B	US-6,265,885 B1	07-2001	Luo et al.	324/719
C	US-6,813,665 B2	11-2004	Rankin et al.	710/260
D	US-6,219,741 B1	04-2001	Pawlowski et al.	710/260
E	US-6,189,065 B1	02-2001	Arndt et al.	710/260
F	US-5,382,950 A	01-1995	Gronemeyer, Michael	340/825.5
G	US-2003/0105798 A1	06-2003	Kim et al.	709/105
H	US-5,446,910 A	08-1995	Kennedy et al.	710/119
I	US-2003/0120702 A1	06-2003	Jahnke, Steven R.	709/102
J	US-2005/0078694 A1	04-2005	Oner, Koray	370/412
K	US-			
L	US-			
M	US-			

**FOREIGN PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N	JP 08-329022	12-1996	Japan	Tomota Masanori	G06F 15/16
O					
P					
Q					
R					
S					
T					

**NON-PATENT DOCUMENTS**

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
U	
V	
W	
X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.